# CAT24C256

# 256 kb I²C CMOS Serial EEPROM

### Description

The CAT24C256 is a 256 kb Serial CMOS EEPROM, internally organized as 32,768 words of 8 bits each.

It features a 64−byte page write buffer and supports the Standard (100 kHz), Fast (400 kHz) and Fast−Plus (1 MHz) I²C protocol.

Write operations can be inhibited by taking the WP pin High (this protects the entire memory).

External address pins make it possible to address up to eight CAT24C256 devices on the same bus.

### Features

- Supports Standard, Fast and Fast−Plus I²C Protocol
- 1.8 V to 5.5 V Supply Voltage Range
- 64−Byte Page Write Buffer
- Hardware Write Protection for Entire Memory
- Schmitt Triggers and Noise Suppression Filters on I²C Bus Inputs (SCL and SDA)
- Low Power CMOS Technology
- 1,000,000 Program/Erase Cycles
- 100 Year Data Retention
- Industrial and Extended Temperature Range
- PDIP, SOIC, TSSOP, MSOP 8−Lead and TDFN, UDFN 8−Pad Packages
- This Device is Pb−Free, Halogen Free/BFR Free, and RoHS Compliant

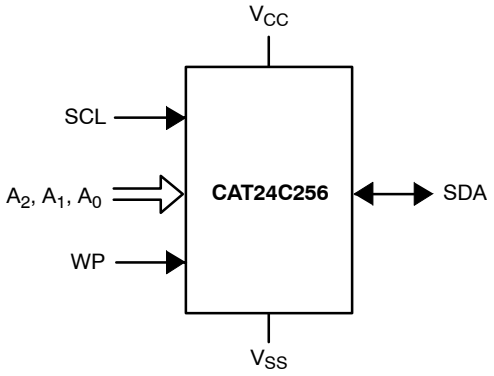
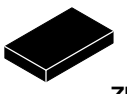


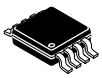

**Figure 1. Functional Symbol**

**ON Semiconductor®**

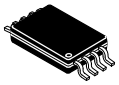
**http://onsemi.com**



**TDFN−8***
**ZD2 SUFFIX**
**CASE 511AM**



**SOIC−8**
**X SUFFIX**
**CASE 751BE**



**TSSOP−8**
**Y SUFFIX**
**CASE 948AL**

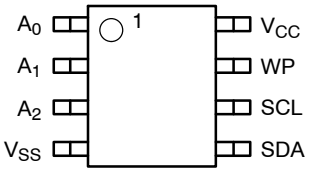
**SOIC−8**
**W SUFFIX**
**CASE 751BD**

**UDFN−8**
**HU4 SUFFIX**
**CASE 517AZ**

**PDIP−8**
**L SUFFIX**
**CASE 646AA**

**MSOP−8**
**Z SUFFIX**
**CASE 846AD**

### PIN CONFIGURATION




PDIP (L), SOIC (W, X), TSSOP (Y),
TDFN (ZD2)*, UDFN (HU4), MSOP (Z)

For the location of Pin 1, please consult the corresponding package drawing.

* Not recommended for new designs

### PIN FUNCTION

| Pin Name | Function |
|---|---|
| $A_0$, $A_1$, $A_2$ | Device Address |
| SDA | Serial Data |
| SCL | Serial Clock |
| WP | Write Protect |
| $V_{CC}$ | Power Supply |
| $V_{SS}$ | Ground |

### ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 18 of this data sheet.

**Table 1. ABSOLUTE MAXIMUM RATINGS**

| Parameters | Ratings | Units |
|---|---|---|
| Storage Temperature | −65 to +150 | °C |
| Voltage on any Pin with Respect to Ground (Note 1) | −0.5 to +6.5 | V |

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. The DC input voltage on any pin should not be lower than −0.5 V or higher than $V_{CC}$ + 0.5 V. During transitions, the voltage on any pin may undershoot to no less than −1.5 V or overshoot to no more than $V_{CC}$ + 1.5 V, for periods of less than 20 ns.

**Table 2. RELIABILITY CHARACTERISTICS** (Note 2)

| Symbol | Parameter | Min | Units |
|---|---|---|---|
| $N_{END}$ (Note 3) | Endurance | 1,000,000 | Program/Erase Cycles |
| $T_{DR}$ | Data Retention | 100 | Years |

2. These parameters are tested initially and after a design or process change that affects the parameter according to appropriate AEC−Q100 and JEDEC test methods.
3. Page Mode, $V_{CC}$ = 5 V, 25°C.

**Table 3. D.C. OPERATING CHARACTERISTICS − Mature Product (Rev D)**

($V_{CC}$ = 2.5 V to 5.5 V, $T_A$ = −40°C to +125°C, and $V_{CC}$ = 1.8 V to 5.5 V, $T_A$ = −40°C to +85°C, unless otherwise specified.)

| Symbol | Parameter | Test Conditions | | Min | Max | Units |
|---|---|---|---|---|---|---|
| $I_{CCR}$ | Read Current | Read, $f_{SCL}$ = 400 kHz | | | 1 | mA |
| $I_{CC}$ | Write Current | Write, $f_{SCL}$ = 400 kHz | | | 3 | mA |
| $I_{SB}$ | Standby Current | All I/O Pins at GND or $V_{CC}$ | $T_A$ = −40°C to +85°C | | 1 | μA |
| | | | $T_A$ = −40°C to +125°C | | 2 | |
| $I_L$ | I/O Pin Leakage | Pin at GND or $V_{CC}$ | $T_A$ = −40°C to +85°C | | 1 | μA |
| | | | $T_A$ = −40°C to +125°C | | 2 | |
| $V_{IL}$ | Input Low Voltage | | | −0.5 | $V_{CC}$ x 0.3 | V |
| $V_{IH}$ | Input High Voltage | | | $V_{CC}$ x 0.7 | $V_{CC}$ + 0.5 | V |
| $V_{OL1}$ | Output Low Voltage | $V_{CC} \geq$ 2.5 V, $I_{OL}$ = 3.0 mA | | | 0.4 | V |
| $V_{OL2}$ | Output Low Voltage | $V_{CC}$ < 2.5 V, $I_{OL}$ = 1.0 mA | | | 0.2 | V |

**Table 4. PIN IMPEDANCE CHARACTERISTICS − Mature Product (Rev D)**

($V_{CC}$ = 2.5 V to 5.5 V, $T_A$ = −40°C to +125°C, and $V_{CC}$ = 1.8 V to 5.5 V, $T_A$ = −40°C to +85°C, unless otherwise specified.)

| Symbol | Parameter | Conditions | Max | Units |
|---|---|---|---|---|
| $C_{IN}$ (Note 4) | SDA I/O Pin Capacitance | $V_{IN}$ = 0 V | 8 | pF |
| $C_{IN}$ (Note 4) | Input Capacitance (other pins) | $V_{IN}$ = 0 V | 6 | pF |
| $I_{WP}$ (Note 5) | WP Input Current | $V_{IN} < V_{IH}$, $V_{CC}$ = 5.5 V | 130 | μA |
| | | $V_{IN} < V_{IH}$, $V_{CC}$ = 3.3 V | 120 | |
| | | $V_{IN} < V_{IH}$, $V_{CC}$ = 1.8 V | 80 | |
| | | $V_{IN} > V_{IH}$ | 1 | |

4. These parameters are tested initially and after a design or process change that affects the parameter according to appropriate AEC−Q100 and JEDEC test methods.
5. When not driven, the WP pin is pulled down to GND internally. For improved noise immunity, the internal pull−down is relatively strong; therefore the external driver must be able to supply the pull−down current when attempting to drive the input HIGH. To conserve power, as the input level exceeds the trip point of the CMOS input buffer (~ 0.5 x $V_{CC}$), the strong pull−down reverts to a weak current source. The variable WP input impedance is available only for Die Rev. C and higher.

**Table 5. D.C. OPERATING CHARACTERISTICS – New Product (Rev E)** (Note 6)
($V_{CC}$ = 1.8 V to 5.5 V, $T_A$ = −40°C to +85°C and $V_{CC}$ = 2.5 V to 5.5 V, $T_A$ = −40°C to +125°C, unless otherwise specified.)

| Symbol | Parameter | Test Conditions | | Min | Max | Units |
|---|---|---|---|---|---|---|
| $I_{CCR}$ | Read Current | Read, $f_{SCL}$ = 400 kHz/1 MHz | | | 1 | mA |
| $I_{CCW}$ | Write Current | | | | 3 | mA |
| $I_{SB}$ | Standby Current | All I/O Pins at GND or $V_{CC}$ | $T_A$ = −40°C to +85°C | | 2 | μA |
| | | | $T_A$ = −40°C to +125°C | | 5 | |
| $I_L$ | I/O Pin Leakage | Pin at GND or $V_{CC}$ | $T_A$ = −40°C to +85°C | | 1 | μA |
| | | | $T_A$ = −40°C to +125°C | | 2 | |
| $V_{IL1}$ | Input Low Voltage | 2.5 V ≤ $V_{CC}$ ≤ 5.5 V | | −0.5 | 0.3 $V_{CC}$ | V |
| $V_{IL2}$ | Input Low Voltage | 1.8 V ≤ $V_{CC}$ < 2.5 V | | −0.5 | 0.25 $V_{CC}$ | V |
| $V_{IH1}$ | Input High Voltage | 2.5 V ≤ $V_{CC}$ ≤ 5.5 V | | 0.7 $V_{CC}$ | $V_{CC}$ + 0.5 | V |
| $V_{IH2}$ | Input High Voltage | 1.8 V ≤ $V_{CC}$ < 2.5 V | | 0.75 $V_{CC}$ | $V_{CC}$ + 0.5 | V |
| $V_{OL1}$ | Output Low Voltage | $V_{CC}$ ≥ 2.5 V, $I_{OL}$ = 3.0 mA | | | 0.4 | V |
| $V_{OL2}$ | Output Low Voltage | $V_{CC}$ < 2.5 V, $I_{OL}$ = 1.0 mA | | | 0.2 | V |

**Table 6. PIN IMPEDANCE CHARACTERISTICS – New Product (Rev E)** (Note 6)
($V_{CC}$ = 1.8 V to 5.5 V, $T_A$ = −40°C to +85°C and $V_{CC}$ = 2.5 V to 5.5 V, $T_A$ = −40°C to +125°C, unless otherwise specified.)

| Symbol | Parameter | Conditions | Max | Units |
|---|---|---|---|---|
| $C_{IN}$ (Note 7) | SDA I/O Pin Capacitance | $V_{IN}$ = 0 V | 8 | pF |
| $C_{IN}$ (Note 7) | Input Capacitance (other pins) | $V_{IN}$ = 0 V | 6 | pF |
| $I_{WP}$, $I_A$ (Note 8) | WP Input Current, Address Input Current ($A_0$, $A_1$, $A_2$) | $V_{IN}$ < $V_{IH}$, $V_{CC}$ = 5.5 V | 75 | μA |
| | | $V_{IN}$ < $V_{IH}$, $V_{CC}$ = 3.3 V | 50 | |
| | | $V_{IN}$ < $V_{IH}$, $V_{CC}$ = 1.8 V | 25 | |
| | | $V_{IN}$ > $V_{IH}$ | 2 | |

6. The new product Rev E is identified by letter “E” or a dedicated marking code on top of the package.
7. These parameters are tested initially and after a design or process change that affects the parameter according to appropriate AEC−Q100 and JEDEC test methods.
8. When not driven, the WP, $A_0$, $A_1$, $A_2$ pins are pulled down to GND internally. For improved noise immunity, the internal pull−down is relatively strong; therefore the external driver must be able to supply the pull−down current when attempting to drive the input HIGH. To conserve power, as the input level exceeds the trip point of the CMOS input buffer (~ 0.5 x $V_{CC}$), the strong pull−down reverts to a weak current source.

**Table 7. A.C. CHARACTERISTICS – Mature Product (Rev D)** (Notes 9, 10)
($V_{CC}$ = 2.5 V to 5.5 V, $T_A$ = −40°C to +125°C, and $V_{CC}$ = 1.8 V to 5.5 V, $T_A$ = −40°C to +85°C, unless otherwise specified.)

| Symbol | Parameter | Standard | | Fast | | Fast−Plus $V_{CC}$ = 2.5 V − 5.5 V $T_A$ = −40°C to +85°C | | Units |
|---|---|---|---|---|---|---|---|---|
| | | Min | Max | Min | Max | Min | Max | |
| $F_{SCL}$ | Clock Frequency | | 100 | | 400 | | 1,000 | kHz |
| $t_{HD:STA}$ | START Condition Hold Time | 4 | | 0.6 | | 0.25 | | μs |
| $t_{LOW}$ | Low Period of SCL Clock | 4.7 | | 1.3 | | 0.55 | | μs |
| $t_{HIGH}$ | High Period of SCL Clock | 4 | | 0.6 | | 0.25 | | μs |
| $t_{SU:STA}$ | START Condition Setup Time | 4.7 | | 0.6 | | 0.25 | | μs |
| $t_{HD:DAT}$ | Data In Hold Time | 0 | | 0 | | 0 | | μs |
| $t_{SU:DAT}$ | Data In Setup Time | 250 | | 100 | | 50 | | ns |
| $t_R$ (Note 11) | SDA and SCL Rise Time | | 1,000 | | 300 | | 100 | ns |
| $t_F$ (Note 11) | SDA and SCL Fall Time | | 300 | | 300 | | 100 | ns |
| $t_{SU:STO}$ | STOP Condition Setup Time | 4 | | 0.6 | | 0.25 | | μs |
| $t_{BUF}$ | Bus Free Time Between STOP and START | 4.7 | | 1.3 | | 0.5 | | μs |
| $t_{AA}$ | SCL Low to Data Out Valid | | 3.5 | | 0.9 | | 0.50 | μs |
| $t_{DH}$ | Data Out Hold Time | 100 | | 100 | | 50 | | ns |
| $T_i$ (Note 11) | Noise Pulse Filtered at SCL and SDA Inputs | | 100 | | 100 | | 100 | ns |
| $t_{SU:WP}$ | WP Setup Time | 0 | | 0 | | 0 | | μs |
| $t_{HD:WP}$ | WP Hold Time | 2.5 | | 2.5 | | 1 | | μs |
| $t_{WR}$ | Write Cycle Time | | 5 | | 5 | | 5 | ms |
| $t_{PU}$ (Notes 11, 12) | Power-up to Ready Mode | | 1 | | 1 | 0.1 | 1 | ms |

9. The product Rev D is identified by letter “D” or a dedicated marking code on top of the package.
10. Test conditions according to “A.C. Test Conditions” table.
11. Tested initially and after a design or process change that affects this parameter.
12. $t_{PU}$ is the delay between the time $V_{CC}$ is stable and the device is ready to accept commands.

**Table 8. A.C. TEST CONDITIONS**

| | |
|---|---|
| Input Levels | 0.2 x $V_{CC}$ to 0.8 x $V_{CC}$ |
| Input Rise and Fall Times | ≤ 50 ns |
| Input Reference Levels | 0.3 x $V_{CC}$, 0.7 x $V_{CC}$ |
| Output Reference Levels | 0.5 x $V_{CC}$ |
| Output Load | Current Source: $I_L$ = 3 mA ($V_{CC}$ ≥ 2.5 V); $I_L$ = 1 mA ($V_{CC}$ < 2.5 V); $C_L$ = 100 pF |

**Table 9. A.C. CHARACTERISTICS – New Product (Rev E)** (Notes 13, 14)
($V_{CC}$ = 1.8 V to 5.5 V, $T_A$ = −40°C to +85°C and $V_{CC}$ = 2.5 V to 5.5 V, $T_A$ = −40°C to +125°C, unless otherwise specified.)

| Symbol | Parameter | Standard $V_{CC}$ = 1.8 V – 5.5 V | | Fast $V_{CC}$ = 1.8 V – 5.5 V | | Fast–Plus $V_{CC}$ = 2.5 V – 5.5 V $T_A$ = –40°C to +85°C | | Units |
|---|---|---|---|---|---|---|---|---|
| | | Min | Max | Min | Max | Min | Max | |
| $F_{SCL}$ | Clock Frequency | | 100 | | 400 | | 1,000 | kHz |
| $t_{HD:STA}$ | START Condition Hold Time | 4 | | 0.6 | | 0.25 | | μs |
| $t_{LOW}$ | Low Period of SCL Clock | 4.7 | | 1.3 | | 0.45 | | μs |
| $t_{HIGH}$ | High Period of SCL Clock | 4 | | 0.6 | | 0.40 | | μs |
| $t_{SU:STA}$ | START Condition Setup Time | 4.7 | | 0.6 | | 0.25 | | μs |
| $t_{HD:DAT}$ | Data In Hold Time | 0 | | 0 | | 0 | | μs |
| $t_{SU:DAT}$ | Data In Setup Time | 250 | | 100 | | 50 | | ns |
| $t_R$ (Note 15) | SDA and SCL Rise Time | | 1,000 | | 300 | | 100 | ns |
| $t_F$ (Note 15) | SDA and SCL Fall Time | | 300 | | 300 | | 100 | ns |
| $t_{SU:STO}$ | STOP Condition Setup Time | 4 | | 0.6 | | 0.25 | | μs |
| $t_{BUF}$ | Bus Free Time Between STOP and START | 4.7 | | 1.3 | | 0.5 | | μs |
| $t_{AA}$ | SCL Low to Data Out Valid | | 3.5 | | 0.9 | | 0.40 | μs |
| $t_{DH}$ | Data Out Hold Time | 50 | | 50 | | 50 | | ns |
| $T_i$ (Note 15) | Noise Pulse Filtered at SCL and SDA Inputs | | 50 | | 50 | | 50 | ns |
| $t_{SU:WP}$ | WP Setup Time | 0 | | 0 | | 0 | | μs |
| $t_{HD:WP}$ | WP Hold Time | 2.5 | | 2.5 | | 1 | | μs |
| $t_{WR}$ | Write Cycle Time | | 5 | | 5 | | 5 | ms |
| $t_{PU}$ (Notes 15, 16) | Power-up to Ready Mode | | 1 | | 1 | 0.1 | 1 | ms |

13. Test conditions according to “A.C. Test Conditions” table.
14. The New product Rev E is identified by letter “E” or a dedicated marking code on top of the package.
15. Tested initially and after a design or process change that affects this parameter.
16. $t_{PU}$ is the delay between the time $V_{CC}$ is stable and the device is ready to accept commands.

### Power-On Reset (POR)

The CAT24C256 Die Rev. C incorporates Power−On Reset (POR) circuitry which protects the internal logic against powering up in the wrong state.

The device will power up into Standby mode after $V_{CC}$ exceeds the POR trigger level and will power down into Reset mode when $V_{CC}$ drops below the POR trigger level.

***This bi−directional POR behavior protects the device against brown−out failure, following a temporary loss of power.***

### Pin Description

**SCL:** The Serial Clock input pin accepts the Serial Clock signal generated by the Master.

**SDA:** The Serial Data I/O pin receives input data and transmits data stored in EEPROM. In transmit mode, this pin is open drain. Data is acquired on the positive edge, and is delivered on the negative edge of SCL.

**$A_0$, $A_1$ and $A_2$:** The Address pins accept the device address. These pins have on−chip pull−down resistors.

**WP:** The Write Protect input pin inhibits all write operations, when pulled HIGH. This pin has an on−chip pull−down resistor.

### Functional Description

The CAT24C256 supports the Inter−Integrated Circuit ($I^2C$) Bus data transmission protocol, which defines a device that sends data to the bus as a transmitter and a device receiving data as a receiver. Data flow is controlled by a Master device, which generates the serial clock and all START and STOP conditions. The CAT24C256 acts as a Slave device. Master and Slave alternate as either transmitter or receiver. Up to 8 devices may be connected to the bus as determined by the device address inputs $A_0$, $A_1$, and $A_2$.

#### $I^2C$ Bus Protocol

The $I^2C$ bus consists of two ‘wires’, SCL and SDA. The two wires are connected to the $V_{CC}$ supply via pull−up resistors. Master and Slave devices connect to the 2−wire bus via their respective SCL and SDA pins. The transmitting device pulls down the SDA line to ‘transmit’ a ‘0’ and releases it to ‘transmit’ a ‘1’.

Data transfer may be initiated only when the bus is not busy (see A.C. Characteristics).

During data transfer, the SDA line must remain stable while the SCL line is HIGH. An SDA transition while SCL is HIGH will be interpreted as a START or STOP condition (Figure 2).

#### START

The START condition precedes all commands. It consists of a HIGH to LOW transition on SDA while SCL is HIGH. The START acts as a ‘wake−up’ call to all receivers. Absent a START, a Slave will not respond to commands.

#### STOP

The STOP condition completes all commands. It consists of a LOW to HIGH transition on SDA while SCL is HIGH. The STOP starts the internal Write cycle (when following a Write command) or sends the Slave into standby mode (when following a Read command).

#### Device Addressing

The Master initiates data transfer by creating a START condition on the bus. The Master then broadcasts an 8−bit serial Slave address. The first 4 bits of the Slave address are set to 1010, for normal Read/Write operations (Figure 3). The next 3 bits, $A_2$, $A_1$ and $A_0$, select one of 8 possible Slave devices. The last bit, R/W, specifies whether a Read (1) or Write (0) operation is to be performed.

#### Acknowledge

After processing the Slave address, the Slave responds with an acknowledge (ACK) by pulling down the SDA line during the 9th clock cycle (Figure 4). The Slave will also acknowledge the byte address and every data byte presented in Write mode. In Read mode the Slave shifts out a data byte, and then releases the SDA line during the 9th clock cycle. If the Master acknowledges the data, then the Slave continues transmitting. The Master terminates the session by not acknowledging the last data byte (NoACK) and by sending a STOP to the Slave. Bus timing is illustrated in Figure 5.

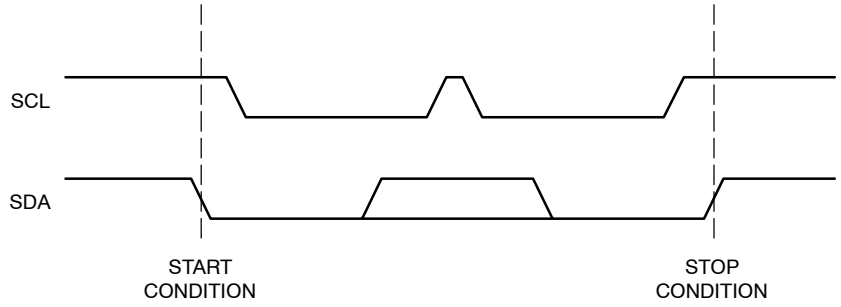



**Figure 2. Start/Stop Timing**

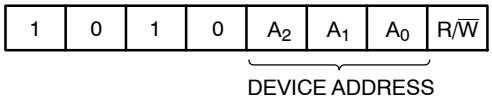



**Figure 3. Slave Address Bits**

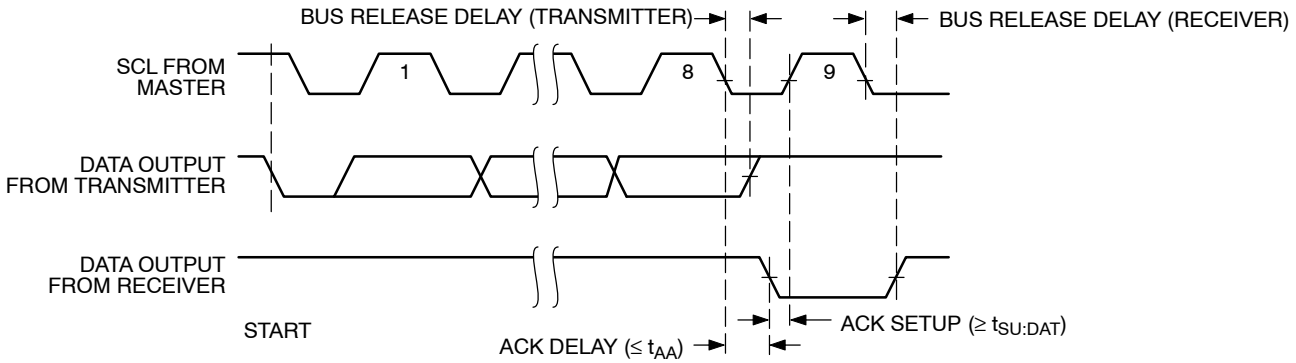



**Figure 4. Acknowledge Timing**

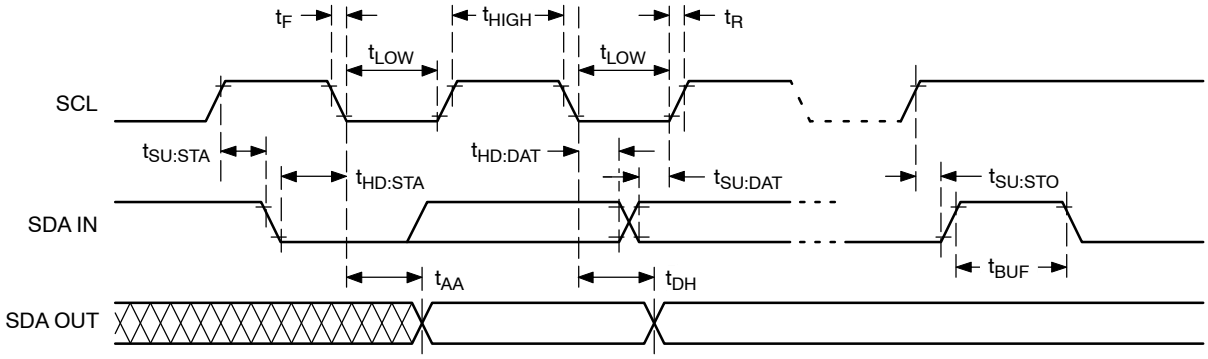



**Figure 5. Bus Timing**

## WRITE OPERATIONS

### Byte Write

In Byte Write mode the Master sends a START, followed by Slave address, two byte address and data to be written (Figure 6). The Slave acknowledges all 4 bytes, and the Master then follows up with a STOP, which in turn starts the internal Write operation (Figure 7). During internal Write, the Slave will not acknowledge any Read or Write request from the Master.

### Page Write

The CAT24C256 contains 32,768 bytes of data, arranged in 512 pages of 64 bytes each. A two byte address word, following the Slave address, points to the first byte to be written. The most significant bit of the address word is ‘don’t care’, the next 9 bits identify the page and the last 6 bits identify the byte within the page. Up to 64 bytes can be written in one Write cycle (Figure 8).

The internal byte address counter is automatically incremented after each data byte is loaded. If the Master transmits more than 64 data bytes, then earlier bytes will be overwritten by later bytes in a ‘wrap−around’ fashion (within the selected page). The internal Write cycle starts immediately following the STOP.

### Acknowledge Polling

Acknowledge polling can be used to determine if the CAT24C256 is busy writing or is ready to accept commands. Polling is implemented by interrogating the device with a ‘Selective Read’ command (see READ OPERATIONS).

The CAT24C256 will not acknowledge the Slave address, as long as internal Write is in progress.

### Hardware Write Protection

With the WP pin held HIGH, the entire memory is protected against Write operations. If the WP pin is left floating or is grounded, it has no impact on the operation of the CAT24C256. The state of the WP pin is strobed on the last falling edge of SCL immediately preceding the first data byte (Figure 9). If the WP pin is HIGH during the strobe interval, the CAT24C256 will not acknowledge the data byte and the Write request will be rejected.

### Delivery State

The CAT24C256 is shipped erased, i.e., all bytes are FFh.

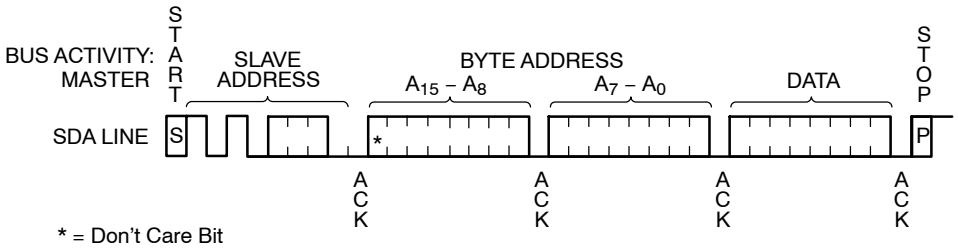



**Figure 6. Byte Write Timing**

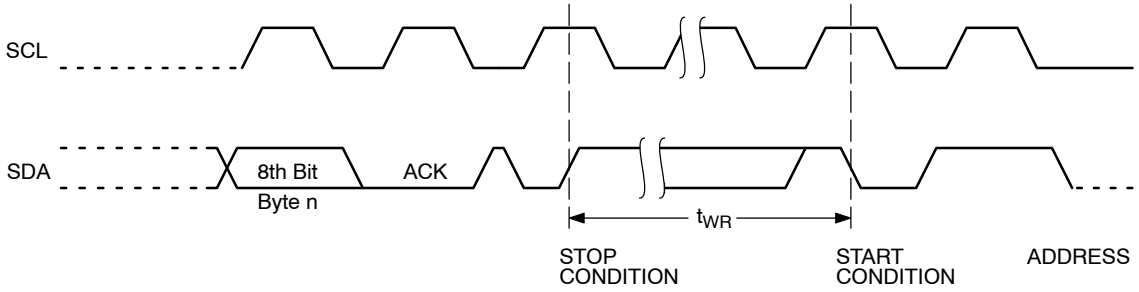



**Figure 7. Write Cycle Timing**

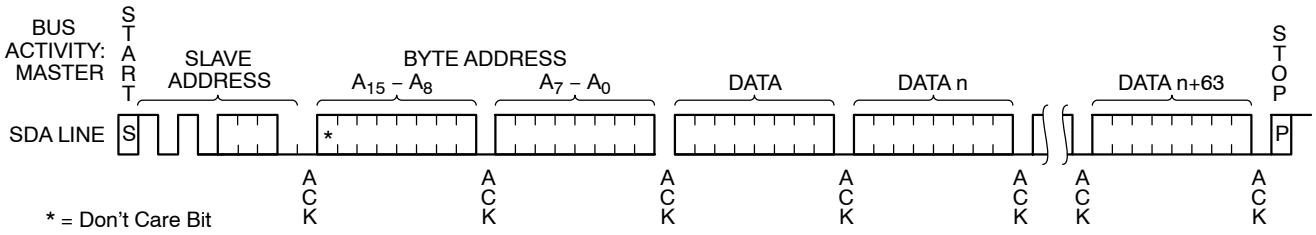



**Figure 8. Page Write Timing**

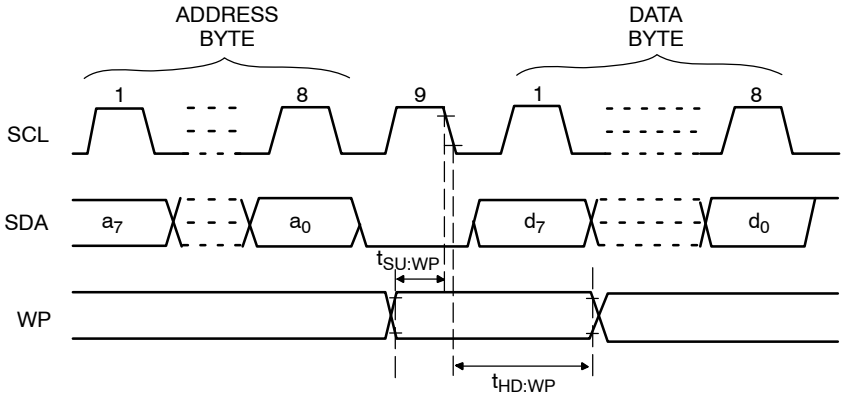



**Figure 9. WP Timing**

## READ OPERATIONS

### Immediate Address Read

In standby mode, the CAT24C256 internal address counter points to the data byte immediately following the last byte accessed by a previous operation. If that 'previous' byte was the last byte in memory, then the address counter will point to the 1st memory byte, etc.

When, following a START, the CAT24C256 is presented with a Slave address containing a '1' in the R/W bit position (Figure 10), it will acknowledge (ACK) in the 9th clock cycle, and will then transmit data being pointed at by the internal address counter. The Master can stop further transmission by issuing a NoACK, followed by a STOP condition.

### Selective Read

The Read operation can also be started at an address different from the one stored in the internal address counter. The address counter can be initialized by performing a 'dummy' Write operation (Figure 11). Here the START is followed by the Slave address (with the R/W bit set to '0') and the desired two byte address. Instead of following up with data, the Master then issues a 2nd START, followed by the 'Immediate Address Read' sequence, as described earlier.

### Sequential Read

If the Master acknowledges the 1st data byte transmitted by the CAT24C256, then the device will continue transmitting as long as each data byte is acknowledged by the Master (Figure 12). If the end of memory is reached during sequential Read, then the address counter will 'wrap−around' to the beginning of memory, etc. Sequential Read works with either 'Immediate Address Read' or 'Selective Read', the only difference being the starting byte address.

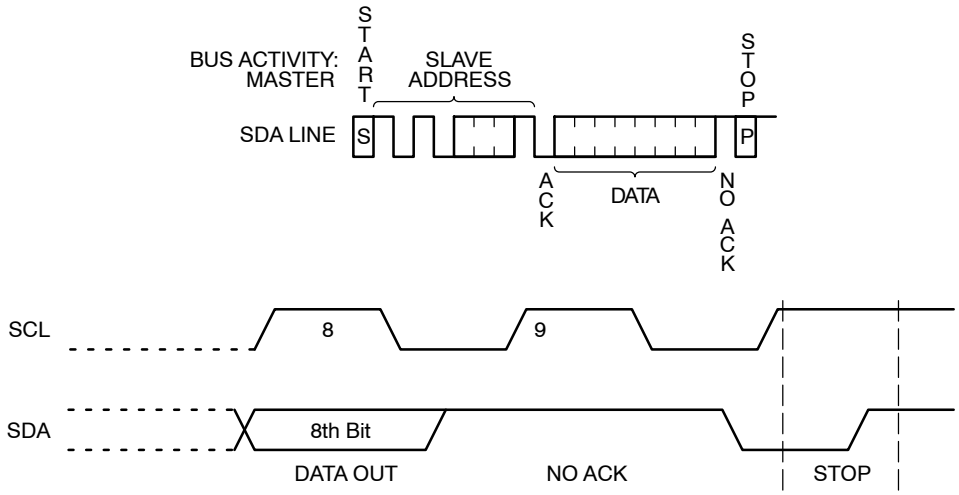



**Figure 10. Immediate Address Read Timing**

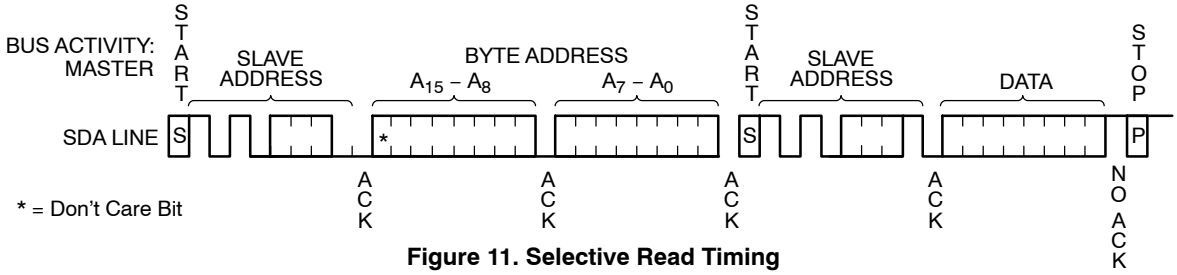



**Figure 11. Selective Read Timing**

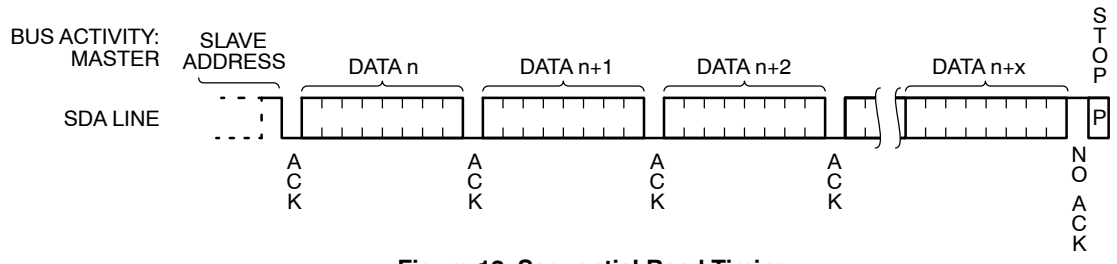
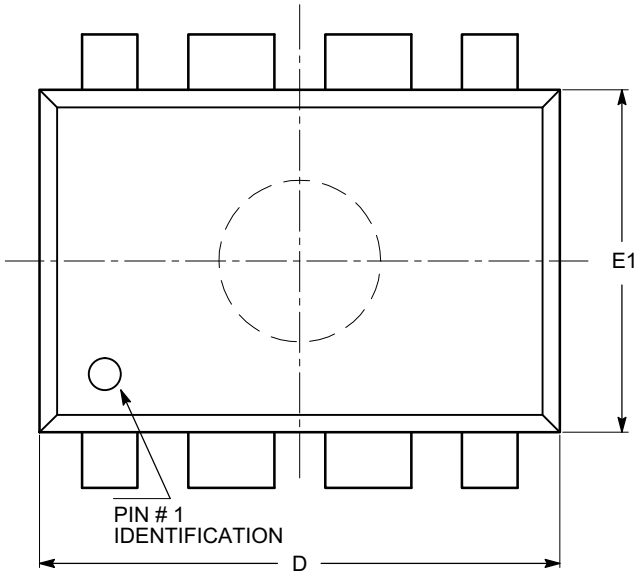



**Figure 12. Sequential Read Timing**

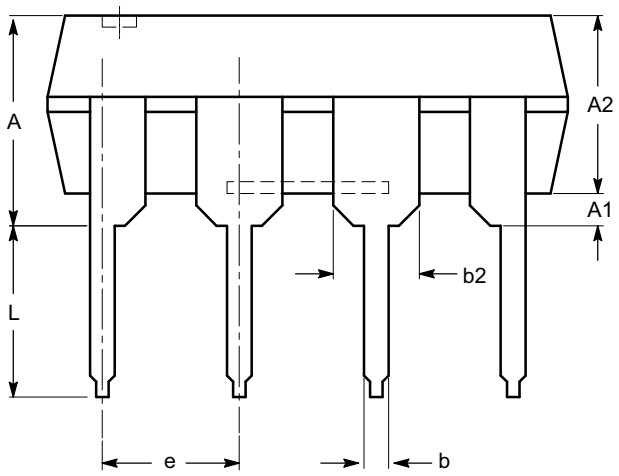
## PACKAGE DIMENSIONS

**PDIP−8, 300 mils**
CASE 646AA−01
ISSUE A

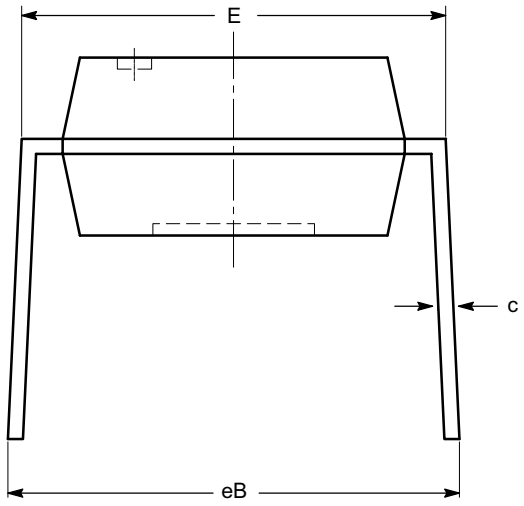



**TOP VIEW**

| SYMBOL | MIN | NOM | MAX |
|---|---|---|---|
| A | | | 5.33 |
| A1 | 0.38 | | |
| A2 | 2.92 | 3.30 | 4.95 |
| b | 0.36 | 0.46 | 0.56 |
| b2 | 1.14 | 1.52 | 1.78 |
| c | 0.20 | 0.25 | 0.36 |
| D | 9.02 | 9.27 | 10.16 |
| E | 7.62 | 7.87 | 8.25 |
| E1 | 6.10 | 6.35 | 7.11 |
| e | | 2.54 BSC | |
| eB | 7.87 | | 10.92 |
| L | 2.92 | 3.30 | 3.80 |




**SIDE VIEW**

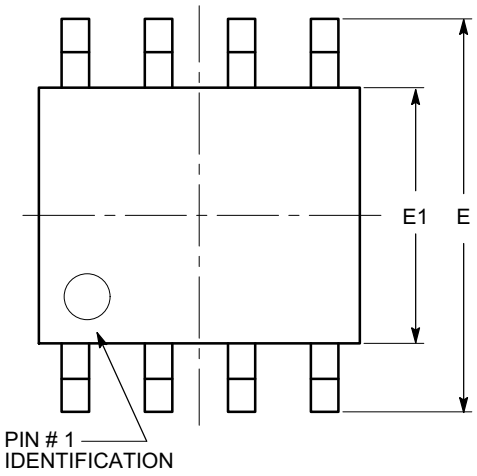



**END VIEW**

**Notes:**
(1) All dimensions are in millimeters.
(2) Complies with JEDEC MS-001.

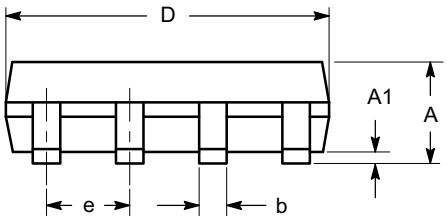
## PACKAGE DIMENSIONS

**SOIC 8, 150 mils**
CASE 751BD−01
ISSUE O

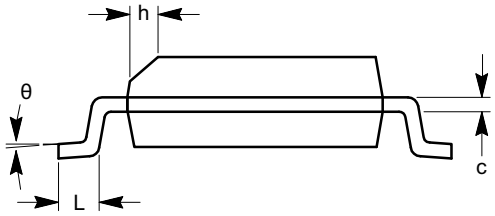



**TOP VIEW**

| SYMBOL | MIN | NOM | MAX |
|---|---|---|---|
| A | 1.35 | | 1.75 |
| A1 | 0.10 | | 0.25 |
| b | 0.33 | | 0.51 |
| c | 0.19 | | 0.25 |
| D | 4.80 | | 5.00 |
| E | 5.80 | | 6.20 |
| E1 | 3.80 | | 4.00 |
| e | | 1.27 BSC | |
| h | 0.25 | | 0.50 |
| L | 0.40 | | 1.27 |
| θ | 0º | | 8º |




**SIDE VIEW**

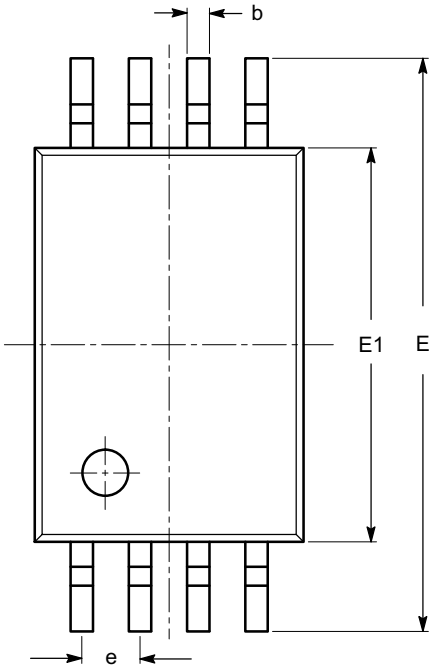



**END VIEW**

**Notes:**
(1) All dimensions are in millimeters. Angles in degrees.
(2) Complies with JEDEC MS-012.

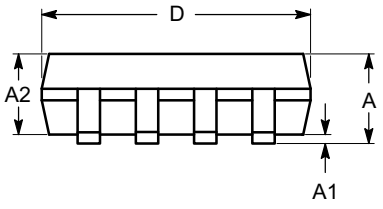
## PACKAGE DIMENSIONS

**TSSOP8, 4.4x3**
CASE 948AL−01
ISSUE O

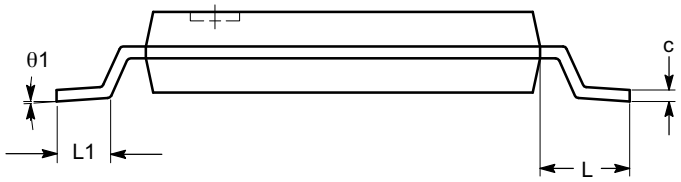



**TOP VIEW**

| SYMBOL | MIN | NOM | MAX |
|---|---|---|---|
| A | | | 1.20 |
| A1 | 0.05 | | 0.15 |
| A2 | 0.80 | 0.90 | 1.05 |
| b | 0.19 | | 0.30 |
| c | 0.09 | | 0.20 |
| D | 2.90 | 3.00 | 3.10 |
| E | 6.30 | 6.40 | 6.50 |
| E1 | 4.30 | 4.40 | 4.50 |
| e | 0.65 BSC | | |
| L | 1.00 REF | | |
| L1 | 0.50 | 0.60 | 0.75 |
| θ | 0° | | 8° |




**SIDE VIEW**

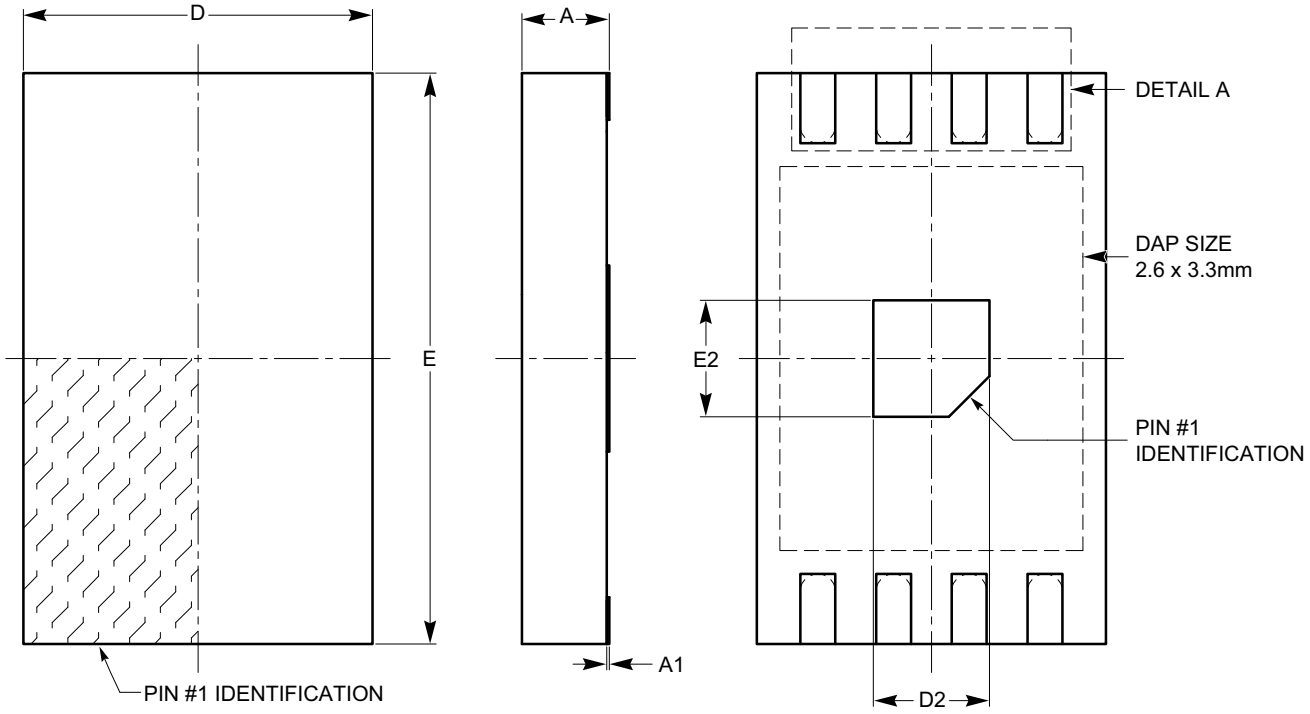



**END VIEW**

**Notes:**
(1) All dimensions are in millimeters. Angles in degrees.
(2) Complies with JEDEC MO-153.

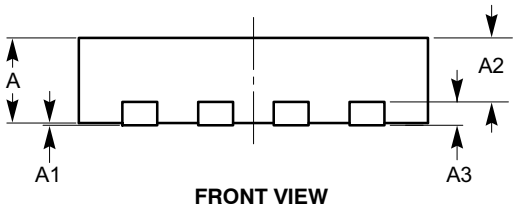
## PACKAGE DIMENSIONS

**TDFN8, 3x4.9**
CASE 511AM−01
ISSUE A

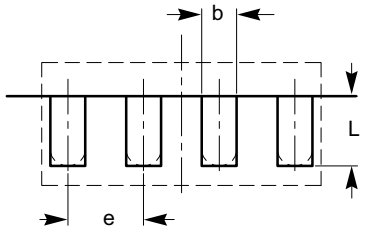



**TOP VIEW** **SIDE VIEW** **BOTTOM VIEW**

| SYMBOL | MIN | NOM | MAX |
|---|---|---|---|
| A | 0.70 | 0.75 | 0.80 |
| A1 | 0.00 | 0.02 | 0.05 |
| A2 | 0.45 | 0.55 | 0.65 |
| A3 | | 0.20 REF | |
| b | 0.25 | 0.30 | 0.35 |
| D | 2.90 | 3.00 | 3.10 |
| D2 | 0.90 | 1.00 | 1.10 |
| E | 4.80 | 4.90 | 5.00 |
| E2 | 0.90 | 1.00 | 1.10 |
| e | | 0.65 TYP | |
| L | 0.50 | 0.60 | 0.70 |




**FRONT VIEW**

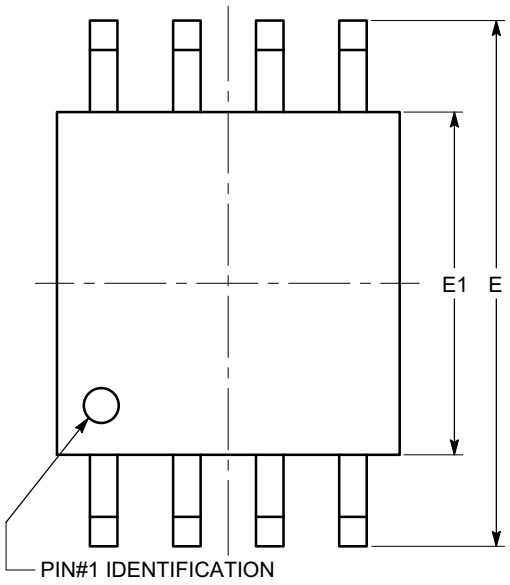



**DETAIL A**

**Notes:**
(1) All dimensions are in millimeters.
(2) Complies with JEDEC MO-229.

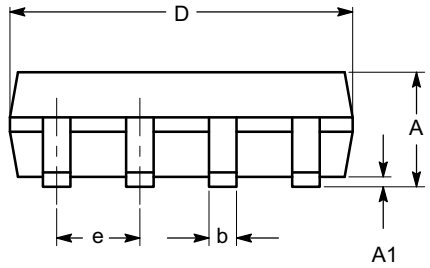
## PACKAGE DIMENSIONS

**SOIC−8, 208 mils**
CASE 751BE−01
ISSUE O

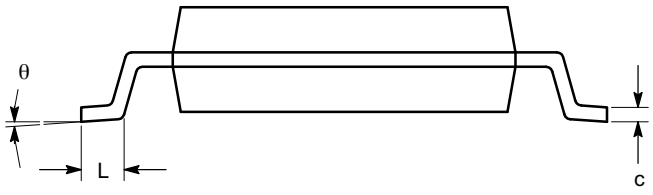



**TOP VIEW**

| SYMBOL | MIN | NOM | MAX |
|---|---|---|---|
| A | | | 2.03 |
| A1 | 0.05 | | 0.25 |
| b | 0.36 | | 0.48 |
| c | 0.19 | | 0.25 |
| D | 5.13 | | 5.33 |
| E | 7.75 | | 8.26 |
| E1 | 5.13 | | 5.38 |
| e | 1.27 BSC | | |
| L | 0.51 | | 0.76 |
| θ | 0° | | 8° |




**SIDE VIEW**

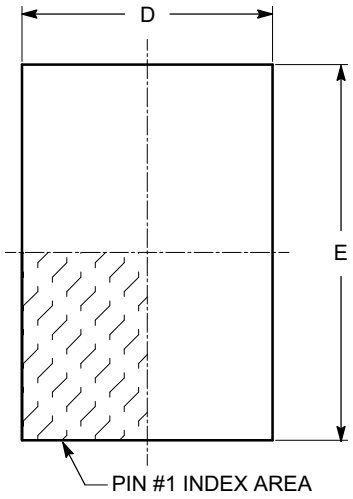



**END VIEW**

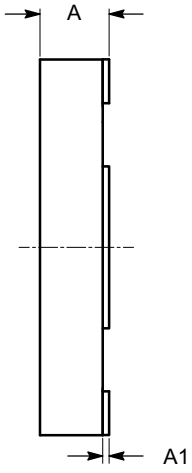
**Notes:**
(1) All dimensions are in millimeters. Angles in degrees.
(2) Complies with EIAJ EDR-7320.

## PACKAGE DIMENSIONS

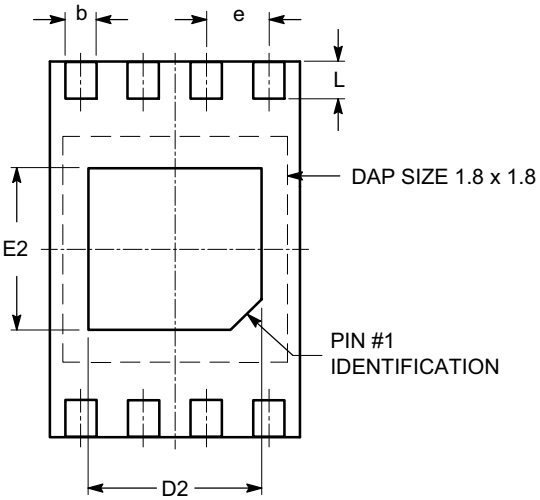
**UDFN8, 2x3 EXTENDED PAD**
CASE 517AZ−01
ISSUE O




**TOP VIEW**



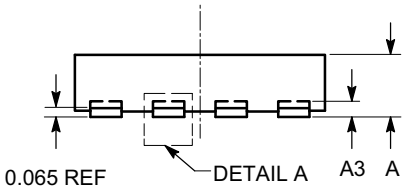

**SIDE VIEW**



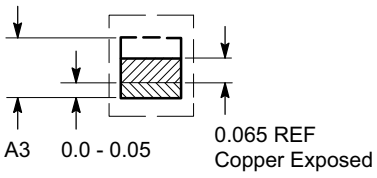

**BOTTOM VIEW**

| SYMBOL | MIN | NOM | MAX |
|---|---|---|---|
| A | 0.45 | 0.50 | 0.55 |
| A1 | 0.00 | 0.02 | 0.05 |
| A3 | | 0.127 REF | |
| b | 0.20 | 0.25 | 0.30 |
| D | 1.95 | 2.00 | 2.05 |
| D2 | 1.35 | 1.40 | 1.45 |
| E | 2.95 | 3.00 | 3.05 |
| E2 | 1.25 | 1.30 | 1.35 |
| e | | 0.50 REF | |
| L | 0.25 | 0.30 | 0.35 |

**Notes:**
(1) All dimensions are in millimeters.
(2) Refer JEDEC MO-236/MO-252.



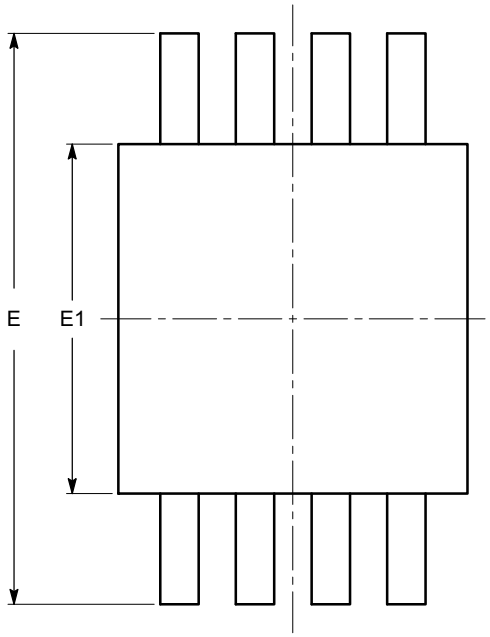

**FRONT VIEW**




**DETAIL A**

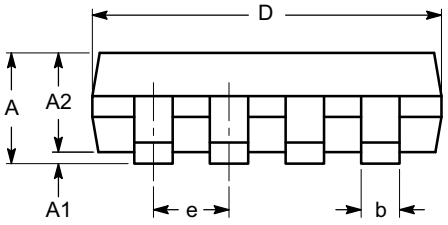
## PACKAGE DIMENSIONS

**MSOP 8, 3x3**
CASE 846AD−01
ISSUE O

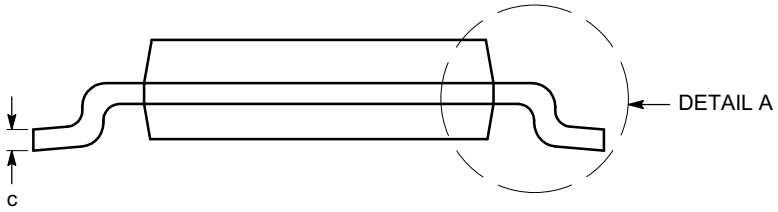



**TOP VIEW**

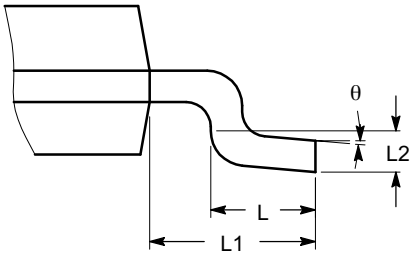
| SYMBOL | MIN | NOM | MAX |
|---|---|---|---|
| A | | | 1.10 |
| A1 | 0.05 | 0.10 | 0.15 |
| A2 | 0.75 | 0.85 | 0.95 |
| b | 0.22 | | 0.38 |
| c | 0.13 | | 0.23 |
| D | 2.90 | 3.00 | 3.10 |
| E | 4.80 | 4.90 | 5.00 |
| E1 | 2.90 | 3.00 | 3.10 |
| e | | 0.65 BSC | |
| L | 0.40 | 0.60 | 0.80 |
| L1 | | 0.95 REF | |
| L2 | | 0.25 BSC | |
| θ | 0° | | 6° |




**SIDE VIEW**



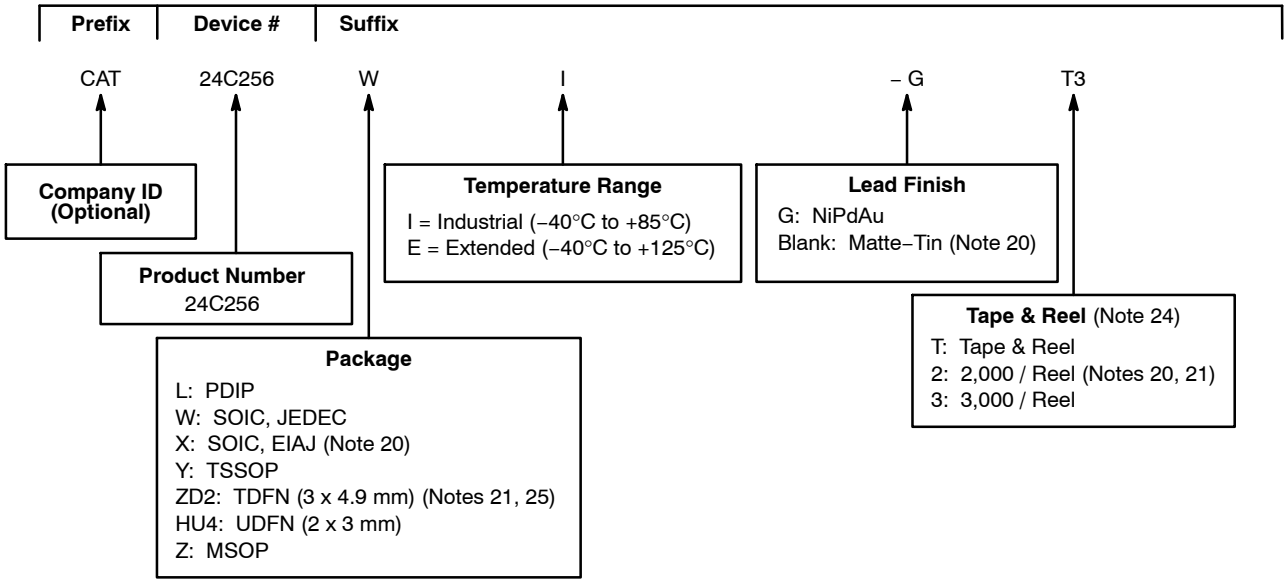

**END VIEW**




**DETAIL A**

**Notes:**
(1) All dimensions are in millimeters. Angles in degrees.
(2) Complies with JEDEC MO-187.

## Example of Ordering Information (Note 19)




## ORDERING INFORMATION

| Orderable Part Numbers | |
|---|---|
| CAT24C256LI–G | CAT24C256LE–G |
| CAT24C256WI–GT3 | CAT24C256WE–GT3 |
| CAT24C256XI–T2 | CAT24C256XE–T2 |
| CAT24C256YI–GT3 | CAT24C256YE–GT3 |
| CAT24C256ZD2IGT2 (Notes 21, 23, 25) | CAT24C256ZD2EGT2 (Notes 21, 23, 25) |
| CAT24C256HU4IGT3 (Note 23) | CAT24C256HU4EGT3 (Note 23) |
| CAT24C256ZI–GT3 | CAT24C256ZE–GT3 |

17. All packages are RoHS-compliant (Lead-free, Halogen-free).
18. The standard lead finish is NiPdAu.
19. The device used in the above example is a CAT24C256WI–GT3 (SOIC–JEDEC, Industrial Temperature, NiPdAu, Tape & Reel, 3,000/Reel).
20. For SOIC, EIAJ (X) package the standard lead finish is Matte–Tin. This package is available in 2,000 pcs/reel, i.e., CAT24C256XI–T2.
21. The TDFN 3 x 4.9 mm (ZD2) package is available in 2,000 pcs/reel, i.e., CAT24C256ZD2IGT2.
22. For additional package and temperature options, please contact your nearest ON Semiconductor Sales office.
23. Part number is not exactly the same as the “Example of Ordering Information” shown above. For part numbers marked with * there are NO hyphens in the orderable part numbers, i.e., CAT24C256HU4IGT3.
24. For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.
25. Not recommended for new design.

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